

Supplementary Information

Shape Evolution of Indium Sulfide Heterostructures via Carbon Nanotube Scrambling: Towards Reliable Sustainability and Mitigating Leakage Current in Supercapacitors

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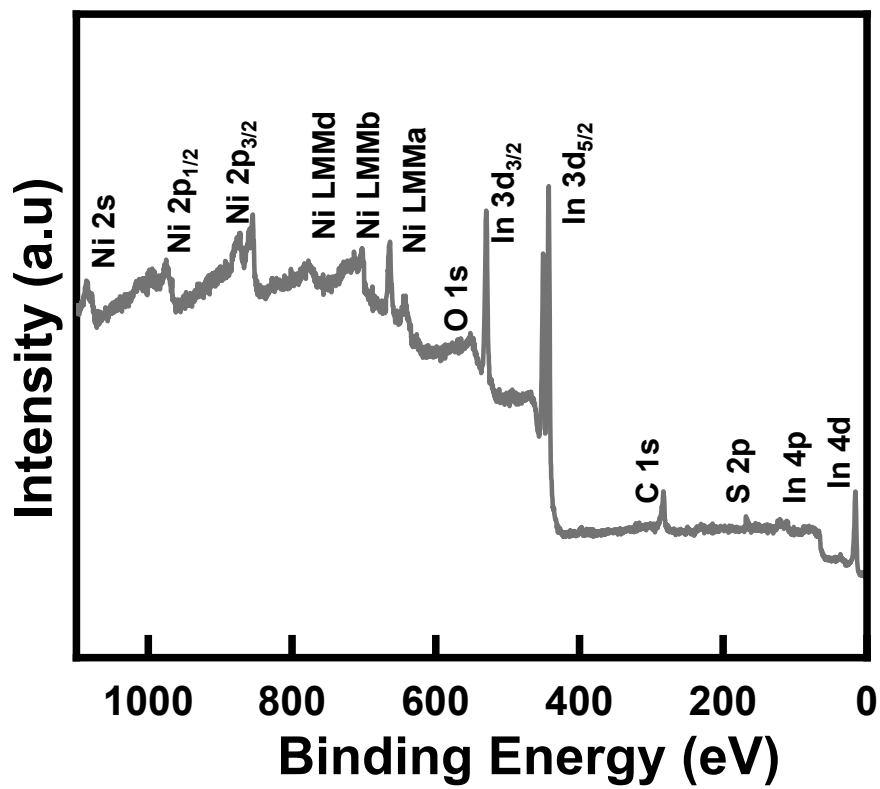


Figure S1. Full scan XPS spectra of INS1 sample.

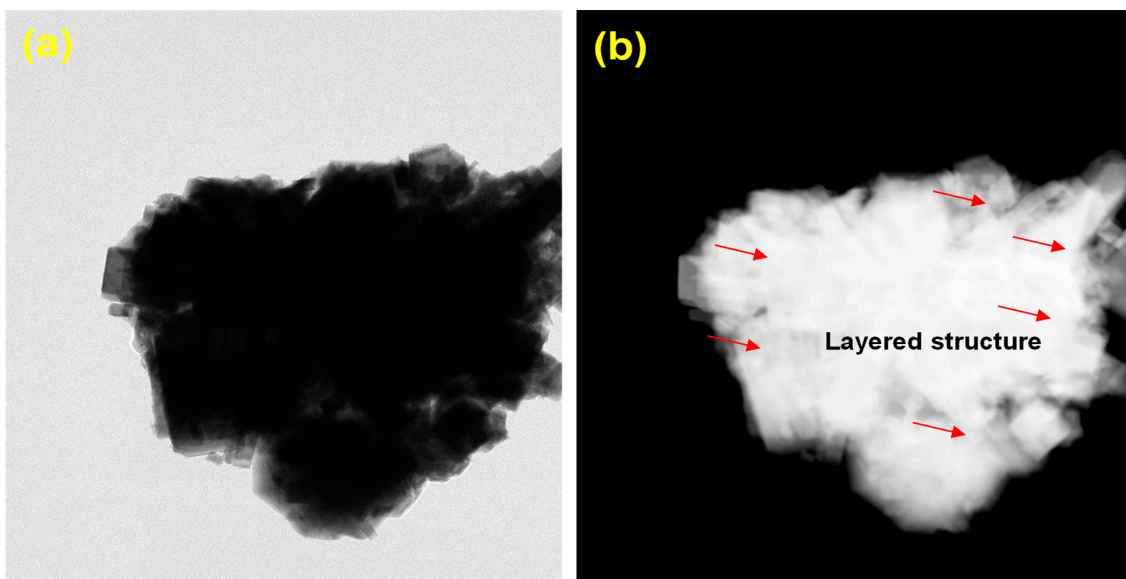


Figure S2. Bright TEM field image (a) HAADF TEM image (b) of INS1 electrode sample.

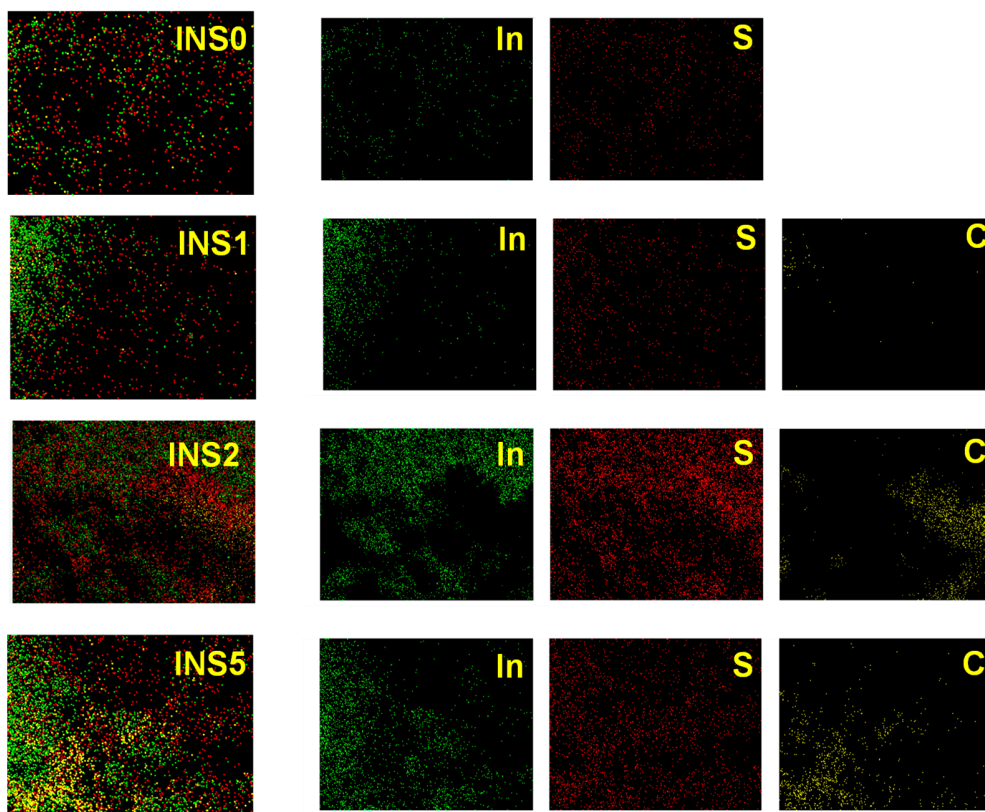


Figure S3. Colour mapping image of INS0, INS1, INS2, and INS5 samples.

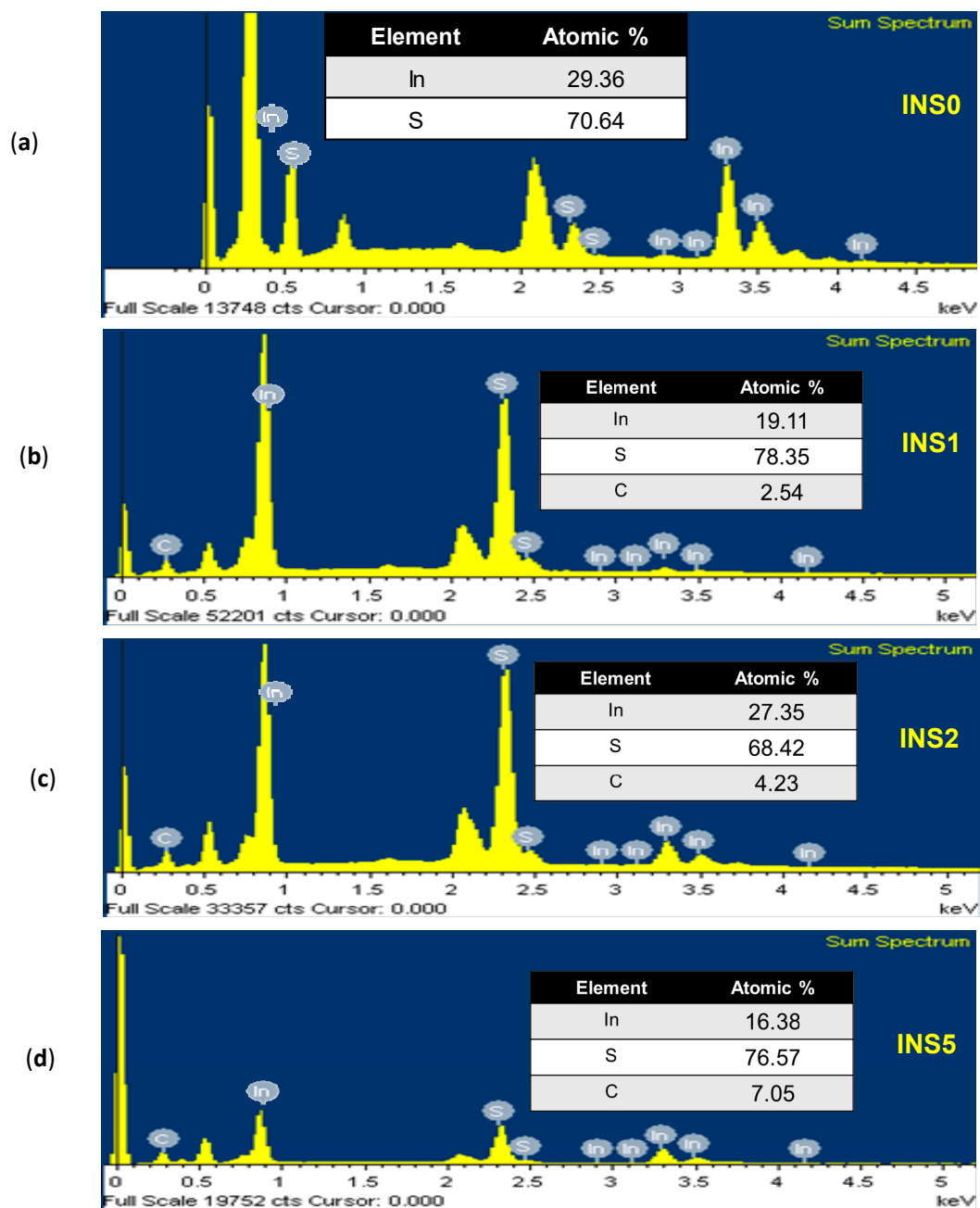


Figure S4. EDAX spectra of (a) INS0, (b) INS1, (c) INS2, and (d) INS5 samples.

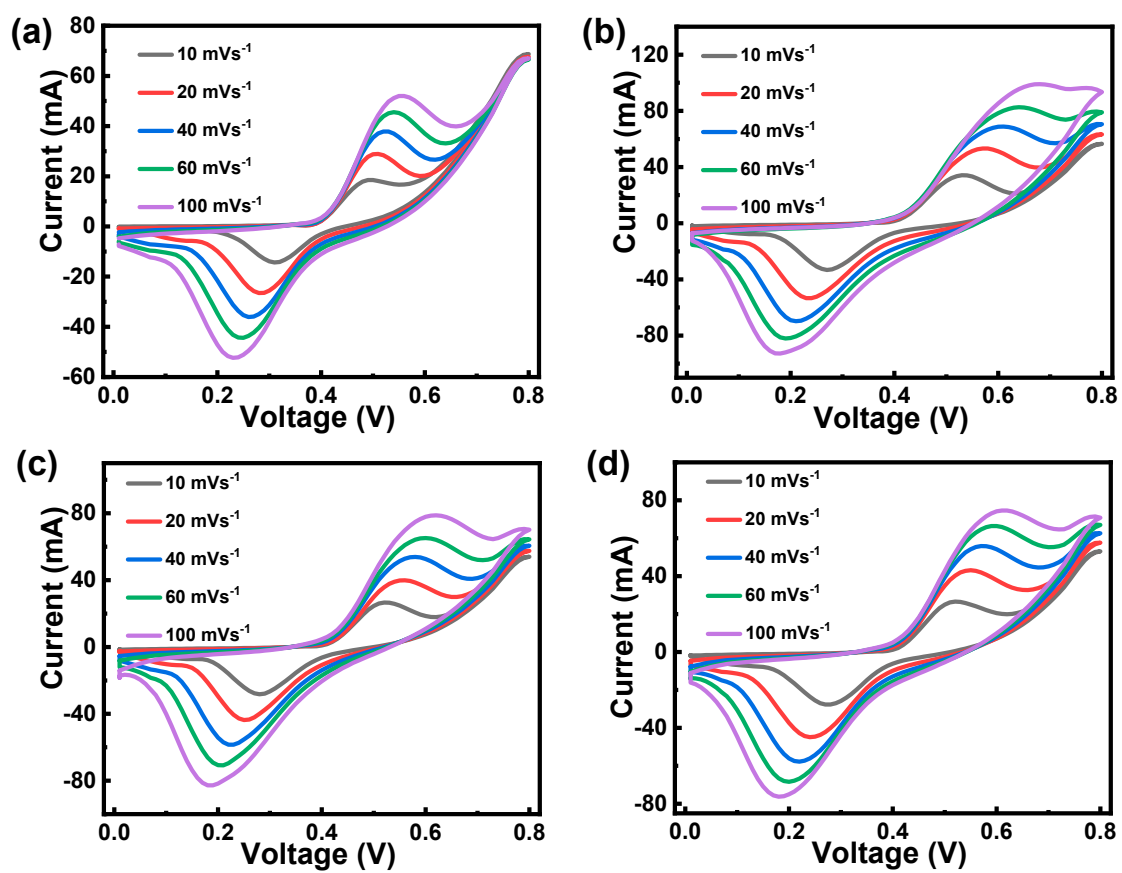


Figure S5. 3T CV curves of (a) INS0, (b) INS1, (c) INS2, and (d) INS5 samples.

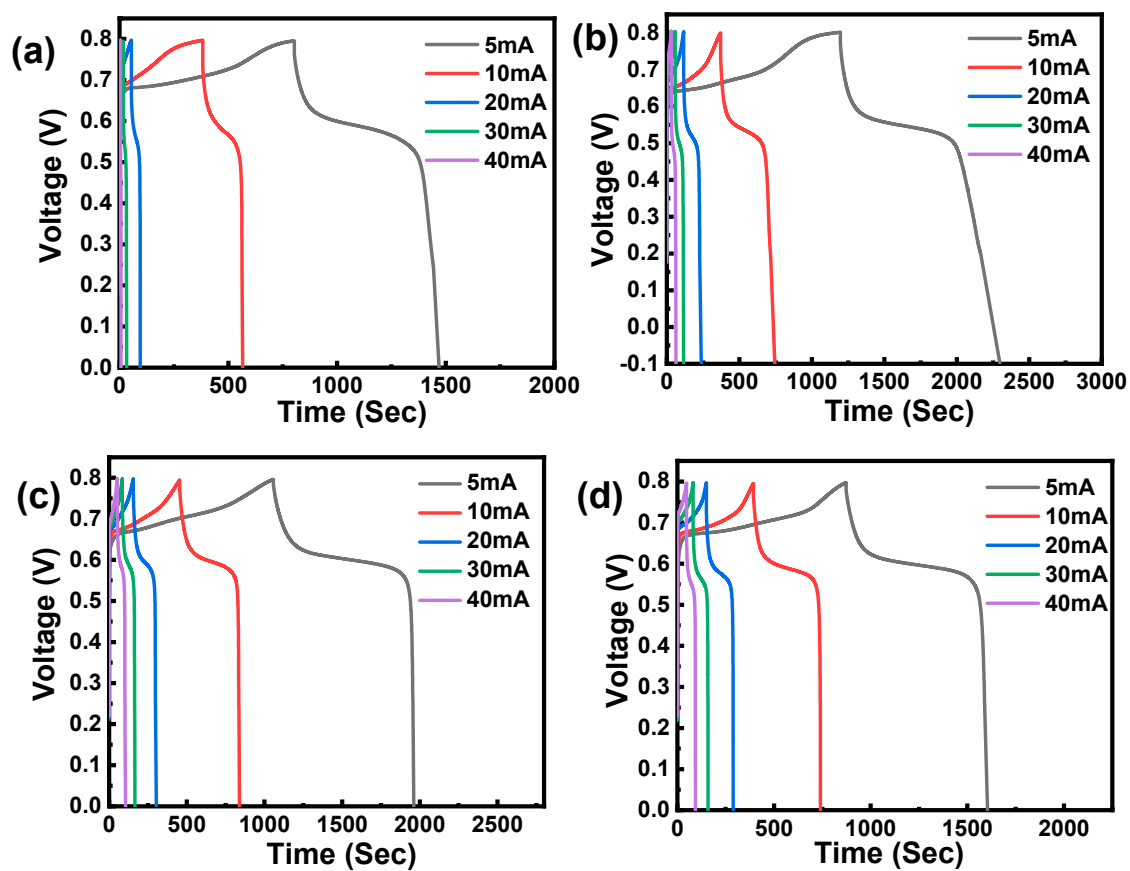


Figure S6. 3T terminal GCD curves of (a) INS0, (b) INS1, (c) INS2, and (d) INS5 samples.

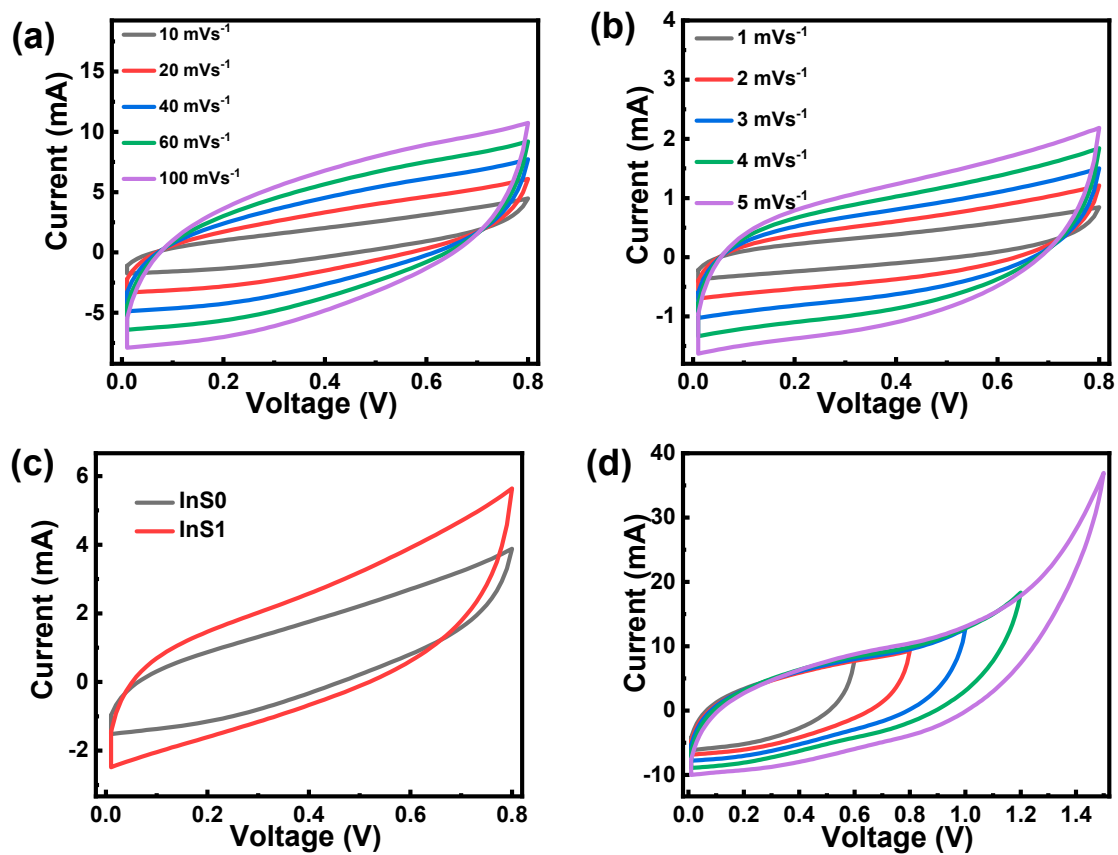


Figure S7. 2T CV curves at (a) higher scan rates (10 mVs⁻¹ to 100 mVs⁻¹) of sample INS0, (b) INS1, (c) comparative CV spectra of INS0 and INS1 (d) CV curve at different potential window of fabricated SSC device.

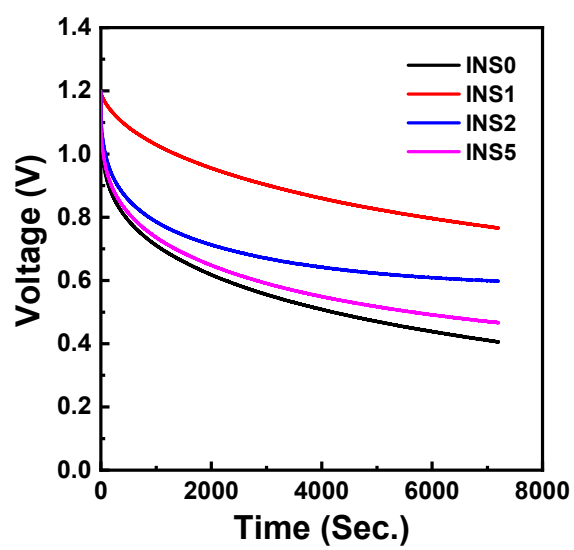


Figure S8. Leakage current spectra of all prepared samples.